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Application/Control No.	Applicant(s)/Patent under Reexamination	
09/847,063	ZHOU ET AL.	
Examiner	Art Unit	
J. Derek Rutten	2192	

	SEARCHED		
Class	Subclass	Date	Examiner
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST (US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB) - see search history printout	11/25/2005	JDR